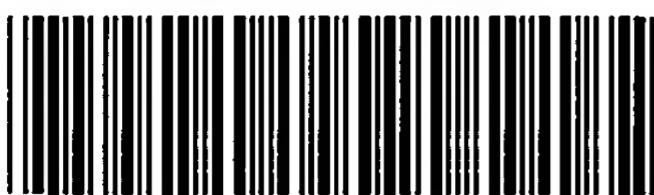


Search Notes



Application/Control No.

10/624.506

Examiner

Edward Wojciechowicz

**Applicant(s)/Patent under
Reexamination**

BYEON ET AL.

Art Unit

2815

SEARCHED

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)